

ADVANCED CERTIFICATE IN APPLIED DIGITAL FORENSIC SCIENCE (CAD4SCI)

The CAD4SCI advanced certificate program is designed for working professionals who are trained in computer science and who wish to develop knowledge and skills in digital forensics without committing to a full graduate degree program. The curriculum blends study of theory and method with practical, hands-on application.

Current Digital Forensics and Cybersecurity (D4CS) master's students may pursue the advanced certificate as part of their degree program.

REQUIRED COURSES

- FCM 710 Architecture and Vulnerabilities of Operating Systems
- FCM 742 Network Security
- FCM 745 Network Forensics
- FCM 760 Forensic Management of Digital Evidence

TOTAL: 12 Credits

Upon satisfactory completion of the coursework, students take the Applied Digital Forensic Science Qualifying Exam. The advanced certificate is awarded to students who complete the required courses with grades of "B" or better and who score a grade of "Pass" or better on the exam.

HOW TO APPLY

For more information regarding the application process, please visit the Graduate Admissions website at www.jjay.cuny.edu/graduate.

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FEATURES OF THE PROGRAM

- Graduate level stand-alone certificate
- Requires 12 credits and a qualifying exam to complete
- New York State Education Department certificate awarded upon completion

ADMISSION REQUIREMENTS

Admission to the advanced certificate program will be based upon the following criteria:

- Undergraduate computer science coursework consisting of at least two courses in programming and courses in data structures, algorithms, operating systems, computer networks, statistics, and discrete math
- A bachelor's degree with a cumulative GPA of 3.0 or higher
- GRE verbal and math scores above the median
- GRE analytical writing score of 4.0 or higher
- Personal statement
- Appropriate letters of recommendation

CONTACT INFORMATION

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